## JANUARY 2002

FDP6644S/FDB6644S

FAIRCHILD

SEMICONDUCTOR®

## FDP6644S/FDB6644S

## 30V N-Channel PowerTrench<sup>®</sup> SyncFET<sup>™</sup>

## **General Description**

This MOSFET is designed to replace a single MOSFET and parallel Schottky diode in synchronous DC:DC power supplies. This 30V MOSFET is designed to maximize power conversion efficiency, providing a low  $R_{\text{DS}(ON)}$  and low gate charge. The FDP6644S includes an integrated Schottky diode using Fairchild's monolithic SyncFET technology. The performance of the FDP6644S/FDB6644S as the low-side switch in a synchronous rectifier is indistinguishable from the performance of the FDP6644/FDB6644 in parallel with a Schottky diode.

## Features

- 28 A, 30 V.  $R_{DS(ON)} = 10 \text{ m}\Omega @ V_{GS} = 10 \text{ V}$  $R_{DS(ON)} = 12 \text{ m}\Omega @ V_{GS} = 4.5 \text{ V}$
- Includes SyncFET Schottky body diode
- Low gate charge (27nC typical)
- High performance trench technology for extremely low R<sub>DS(ON)</sub> and fast switching
- High power and current handling capability



## Absolute Maximum Ratings T<sub>A</sub>=25°C unless otherwise noted

Symbol	Parameter	Ratings	Units
V <sub>DSS</sub>	Drain-Source Voltage	30	V
V <sub>GSS</sub>	Gate-Source Voltage	±16	V
I <sub>D</sub>	Drain Current – Continuous (Note 1)	55	A
	– Pulsed (Note 1)	150	
PD	Total Power Dissipation @ T <sub>c</sub> = 25°C	60	W
	Derate above 25°C	0.48	W/°C
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temperature Range	-65 to +125	°C
TL	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds	275	۵°
Therma	I Characteristics		
Reic	Thermal Resistance Junction-to-Case	21	°C/W

$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	2.1	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	62.5	°C/W

## Package Marking and Ordering Information

Device Marking	Device	Reel Size	Tape width	Quantity
FDB6644S	FDB6644S	13"	24mm	800 units
FDP6644S	FDP6644S	Tube	n/a	45

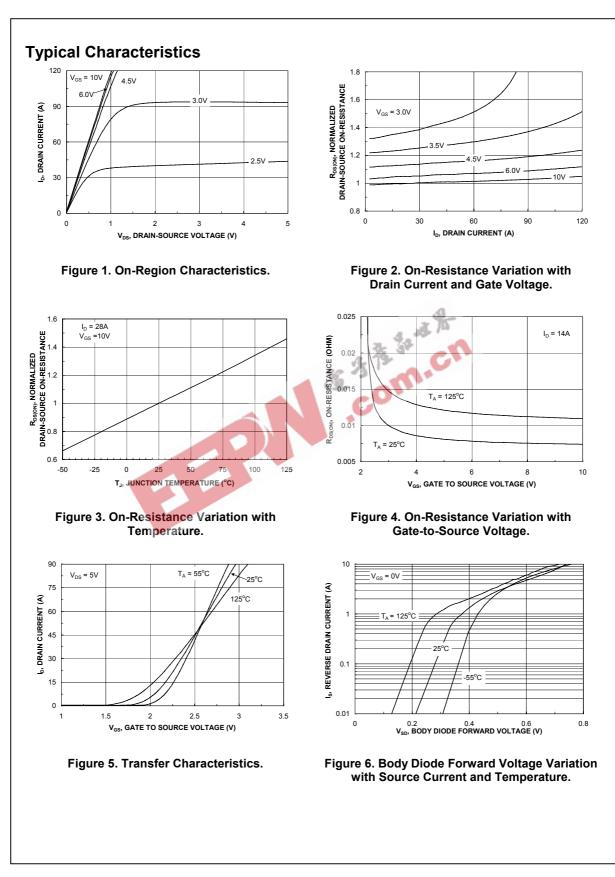
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Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Char	acteristics	•				
BV <sub>DSS</sub>	Drain–Source Breakdown Voltage	$V_{GS} = 0 V$ , $I_D = 1mA$	30			V
$\frac{\Delta BV_{DSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	$I_D$ = 10mA, Referenced to 25°C		23		mV/°0
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	$V_{DS} = 24 V$ , $V_{GS} = 0 V$			500	uA
I <sub>GSSF</sub>	Gate–Body Leakage, Forward	V <sub>GS</sub> = 16 V, V <sub>DS</sub> = 0 V			100	nA
I <sub>GSSR</sub>	Gate–Body Leakage, Reverse	$V_{GS} = -16 V V_{DS} = 0 V$			-100	nA
On Char	acteristics (Note 2)					
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 1mA$	1	1.3	3	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate Threshold Voltage Temperature Coefficient	$I_D$ = 10mA, Referenced to 25°C		-9.5		mV/°0
R <sub>DS(on)</sub>	Static Drain–Source On–Resistance		G	7 8 11.5	10 12 17	mΩ
I <sub>D(on)</sub>	On-State Drain Current	$V_{GS}$ = 10 V, $V_{DS}$ = 5 V	60			Α
<b>g</b> fs	Forward Transconductance	$V_{DS} = 5 V$ , $I_{D} = 28 A$	-	89		S
Dynamic	Characteristics	2 2 12				
Ciss	Input Capacitance	$V_{DS} = 15 V$ , $V_{GS} = 0 V$ ,		2851		pF
Coss	Output Capacitance	f = 1.0 MHz		540		pF
C <sub>rss</sub>	Reverse Transfer Capacitance			196		pF
Switchin	g Characteristics (Note 2)					
t <sub>d(on)</sub>	Turn–On Delay Time	$V_{DS} = 15 V$ , $I_{D} = 1 A$ ,		12	21	ns
t <sub>r</sub>	Turn–On Rise Time	$\nabla_{\rm GS}$ = 10 V, $R_{\rm GEN}$ = 6 $\Omega$		11	20	ns
t <sub>d(off)</sub>	Turn–Off Delay Time			53	85	ns
t <sub>f</sub>	Turn–Off Fall Time			17	30	ns
Qg	Total Gate Charge	$V_{DS} = 15 V$ , $I_{D} = 28 A$ ,		27	38	nC
Q <sub>gs</sub>	Gate-Source Charge	$V_{GS} = 5 V$		7		nC
Q <sub>gd</sub>	Gate–Drain Charge			8		nC
Drain-Se	ource Diode Characteristics					
V <sub>SD</sub>	Drain–Source Diode Forward Voltage	$ \begin{array}{ll} V_{GS} = 0 \ V, & I_S = 3.5 \ A & (\text{Note 1}) \\ V_{GS} = 0 \ V, & I_S = 7 \ A & (\text{Note 1}) \end{array} $		0.48 0.6	0.7	V
t <sub>rr</sub>	Diode Reverse Recovery Time	I <sub>F</sub> = 28 A,		21		nS
Q <sub>rr</sub>	Diode Reverse Recovery Charge	$d_{iF}/d_t = 300 \text{ A/}\mu\text{s}$ (Note 2)		34		nC

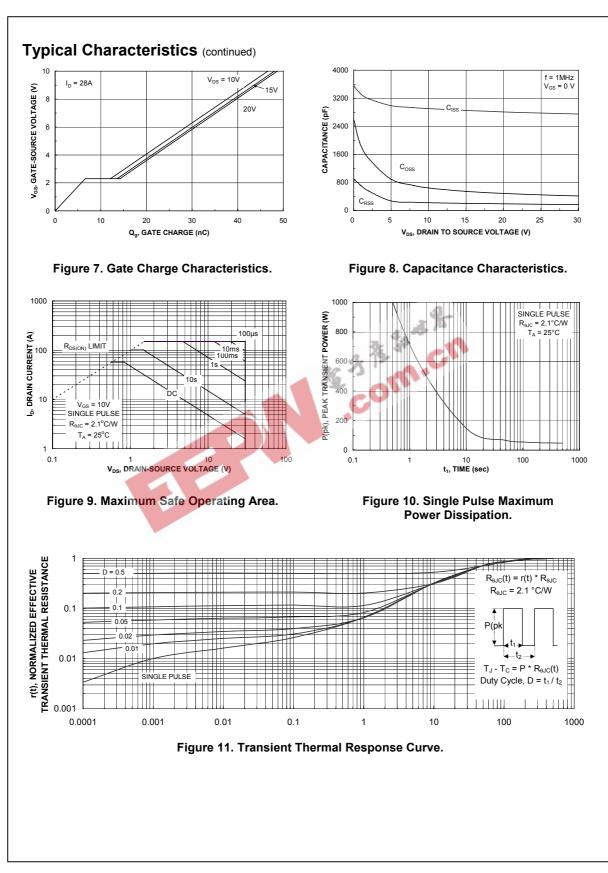
Notes:

Pulse Test: Pulse Width < 300µs, Duty Cycle < 2.0%</li>
See "SyncFET Schottky body diode characteristics" below.

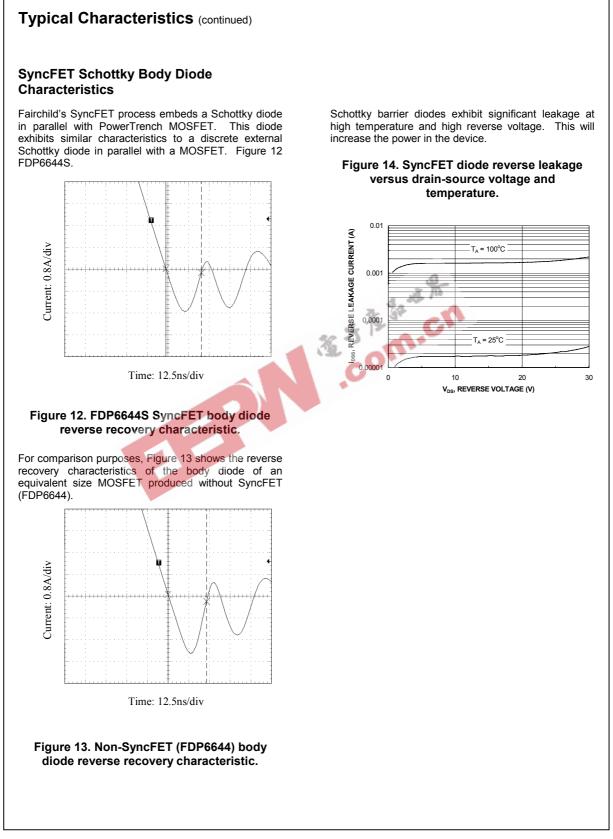
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